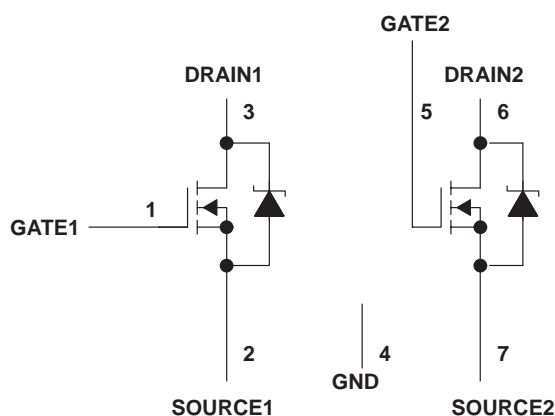


- Two 7.5-A Independent Output Channels, Continuous Current Per Channel
- Low $r_{DS(on)}$. . . 0.09 Ω Typical
- Output Voltage . . . 60 V
- Pulsed Current . . . 15 A Per Channel
- Avalanche Energy . . . 120 mJ

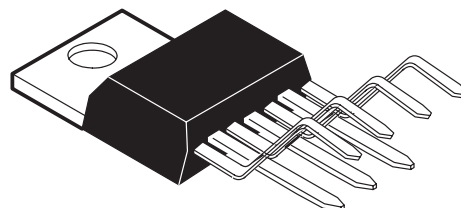
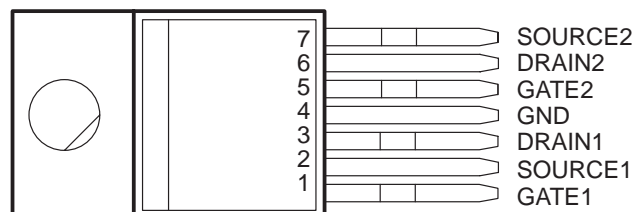
description

The TPIC5201 is a power monolithic DMOS array that consists of dual independent N-channel enhancement-mode DMOS transistors.

schematic



KV PACKAGE
(TOP VIEW)



To ensure correct device operation, the source and the drain of the same transistor cannot simultaneously be taken below GND.

The tab is electrically connected to GND.

absolute maximum ratings over operating case temperature range (unless otherwise noted)

Drain-source voltage, V_{DS}	60 V
Source-GND voltage	60 V
Drain-GND voltage	60 V
Gate-source voltage, V_{GS}	± 20 V
Continuous source-drain diode current	7.5 A
Pulsed drain current, each output, all outputs on, I_D (see Note 1)	15 A
Continuous drain current, each output, all outputs on	7.5 A
Single-pulse avalanche energy, E_{AS} (see Figure 4)	120 mJ
Continuous power dissipation at (or below) $T_A = 25^\circ\text{C}$ (see Note 2)	2 W
Continuous power dissipation at (or below) $T_C = 75^\circ\text{C}$, all outputs on (see Note 2)	31 W
Operating virtual junction temperature range, T_J	-40°C to 150°C
Operating case temperature range, T_C	-40°C to 125°C
Storage temperature range, T_{stg}	-40°C to 125°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

- NOTES: 1. Pulse duration = 10 ms, duty cycle = 6%
2. For operation above 25°C free-air temperature, derate linearly at the rate of 16 mW/ $^\circ\text{C}$. For operation above 75°C case temperature, and with all outputs conducting, derate linearly at the rate of 0.42 W/ $^\circ\text{C}$. To avoid exceeding the design maximum virtual junction temperature, these ratings should not be exceeded.

TPIC5201

DUAL POWER DMOS ARRAY

SLIS020 – SEPTEMBER 1992

electrical characteristics, $T_C = 25^\circ\text{C}$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{(BR)DS}$ Drain-source breakdown voltage	$I_D = 1\ \mu\text{A}$, $V_{GS} = 0$	60			V
V_{TGS} Gate-source threshold voltage	$I_D = 1\ \text{mA}$, $V_{DS} = V_{GS}$	1.2	1.75	2.4	V
$V_{DS(on)}$ Drain-source on-state voltage	$I_D = 7.5\ \text{A}$, $V_{GS} = 15\ \text{V}$, See Notes 3 and 4		0.68	0.94	V
V_{DSS} Zero-gate-voltage drain current	$V_{DS} = 48\ \text{V}$, $V_{GS} = 0$	$T_C = 25^\circ\text{C}$	0.07	1	μA
		$T_C = 125^\circ\text{C}$	1.3	10	
I_{GSSF} Forward gate current, drain short circuited to source	$V_{GS} = 20\ \text{V}$, $V_{DS} = 0$		10	100	nA
I_{GSSR} Reverse gate current, drain short circuited to source	$V_{GS} = -20\ \text{V}$, $V_{DS} = 0$		10	100	nA
$r_{DS(on)}$ Static drain-source on-state resistance	$V_{GS} = 15\ \text{V}$, $I_D = 7.5\ \text{A}$, See Notes 3 and 4 and Figures 5 and 6	$T_C = 25^\circ\text{C}$	0.09	0.125	Ω
		$T_C = 125^\circ\text{C}$	0.15	0.21	
g_{fs} Forward transconductance	$V_{DS} = 15\ \text{V}$, $I_D = 5\ \text{A}$, See Notes 3 and 4	2.5	4.7		S
C_{iss} Short-circuit input capacitance, common source	$V_{DS} = 25\ \text{V}$, $V_{GS} = 0$, $f = 300\ \text{kHz}$		490		pF
C_{oss} Short-circuit output capacitance, common source			285		
C_{rss} Short-circuit reverse transfer capacitance, common source			90		

NOTES: 3. Technique should limit $T_J - T_C$ to 10°C maximum.

4. These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts.

source-drain diode characteristics, $T_C = 25^\circ\text{C}$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{SD} Forward on voltage	$I_S = 7.5\ \text{A}$, $V_{GS} = 0$,		0.8	1.3	V
t_{rr} Reverse-recovery time	$di/dt = 100\ \text{A}/\mu\text{s}$, $V_{DS} = 48\ \text{V}$, See Figure 1		200		ns
Q_{RR} Total source-drain diode charge			1.5		μC

resistive-load switching characteristics, $T_C = 25^\circ\text{C}$

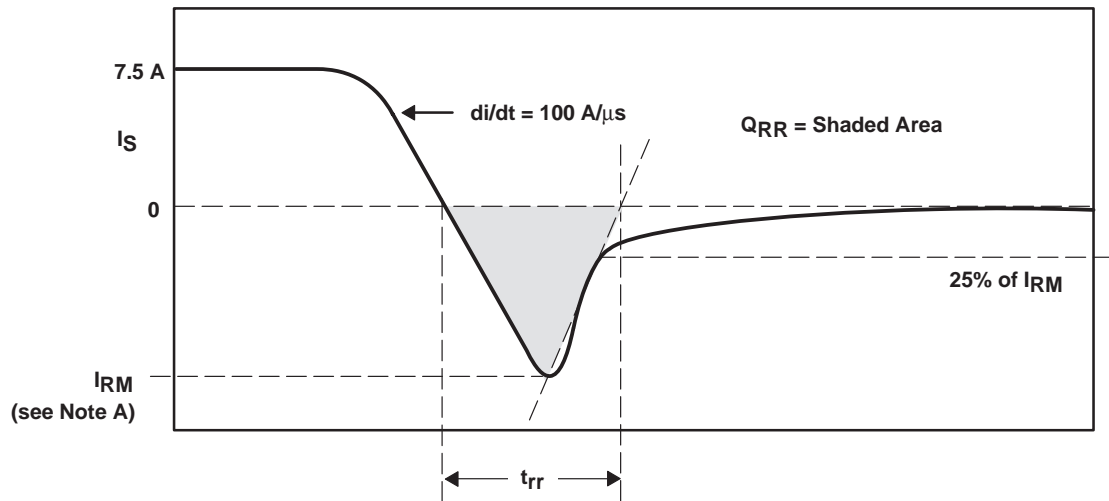
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{d(on)}$ Turn-on delay time	$V_{DD} = 25\ \text{V}$, $R_L = 6.7\ \Omega$, $t_{en} = 10\ \text{ns}$, $t_{dis} = 10\ \text{ns}$, See Figure 2		12		ns
t_r Rise time			43		
$t_{d(off)}$ Turn-off delay time			100		
t_f Fall time			5		
Q_g Total gate charge	$V_{DD} = 48\ \text{V}$, $I_D = 2.5\ \text{A}$, $V_{GS} = 15$, See Figure 3		13.6	18	nC
Q_{gs} Gate-source charge			8.3	11	
Q_{gd} Gate-drain charge			5.3	7	
L_D Internal drain inductance			7		nH
L_S Internal source inductance			7		

thermal resistance

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$R_{\theta JA}$ Junction-to-ambient thermal resistance	All outputs with equal power			62.5	$^\circ\text{C}/\text{W}$
$R_{\theta JC}$ Junction-to-case thermal resistance	All outputs with equal power			2.4	$^\circ\text{C}/\text{W}$
	One output dissipating power			3.3	$^\circ\text{C}/\text{W}$



PARAMETER MEASUREMENT INFORMATION



NOTE A: I_{RM} = maximum recovery current

Figure 1. Reverse-Recovery-Current Waveforms of Source-Drain Diode

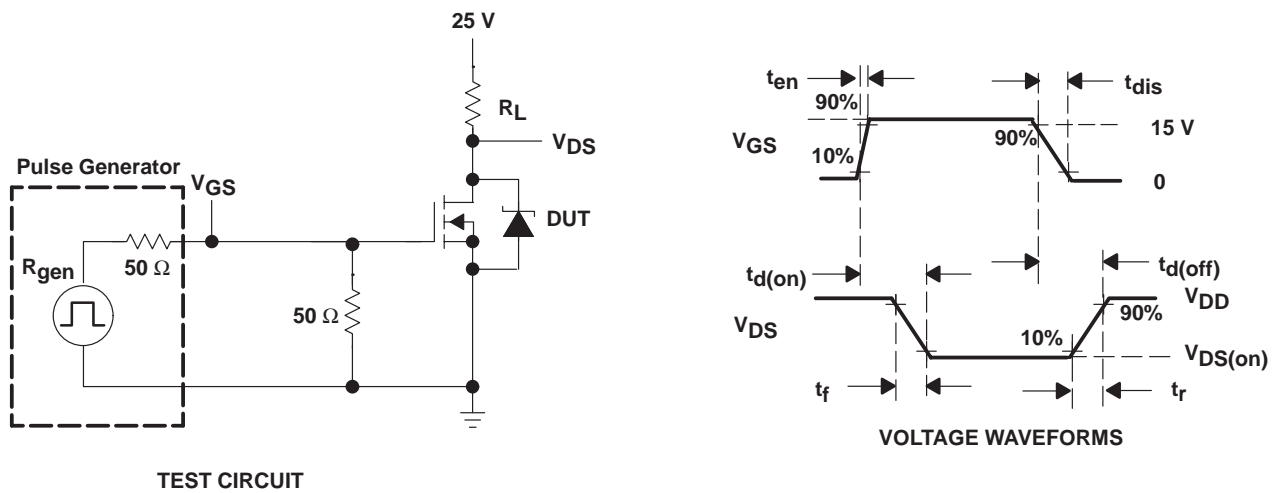


Figure 2. Resistive Switching

PARAMETER MEASUREMENT INFORMATION

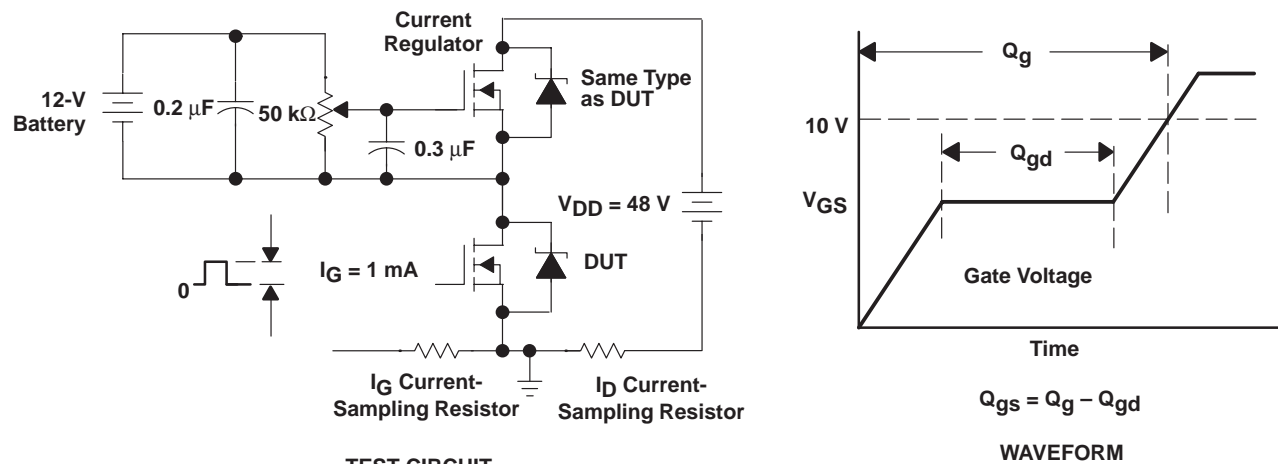
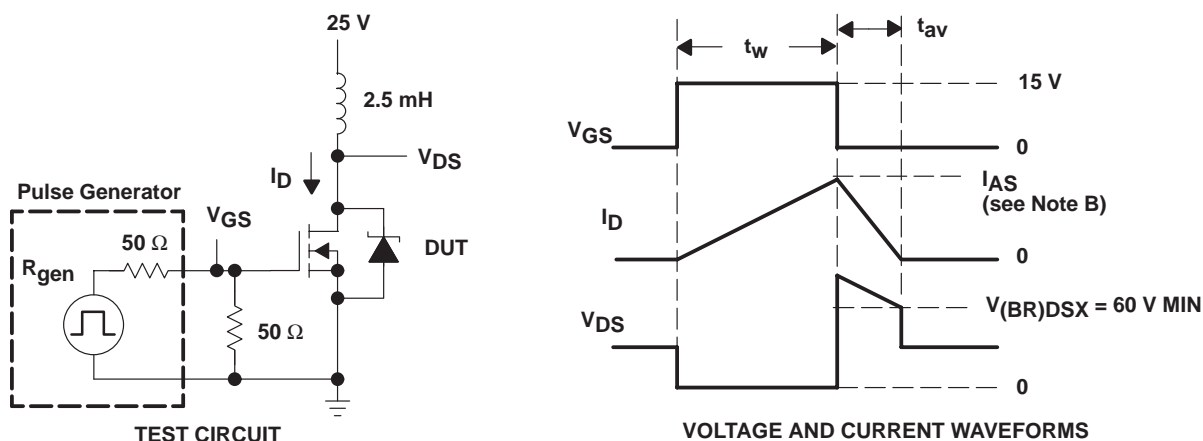


Figure 3. Gate Charge Test Circuit and Waveform



NOTES: A. The pulse generator has the following characteristics: $t_r \leq 10$ ns, $t_f \leq 10$ ns, $Z_O = 50 \Omega$.

B. Input pulse duration (t_w) is increased until peak current $I_{AS} = 7.5$ A.

Energy test level is defined as $E_{AS} = \frac{I_{AS} \times V_{(BR)DSX} \times t_{av}}{2} = 120$ mJ min.

Figure 4. Single-Pulse Avalanche Energy Test Circuit and Waveforms

TYPICAL CHARACTERISTICS

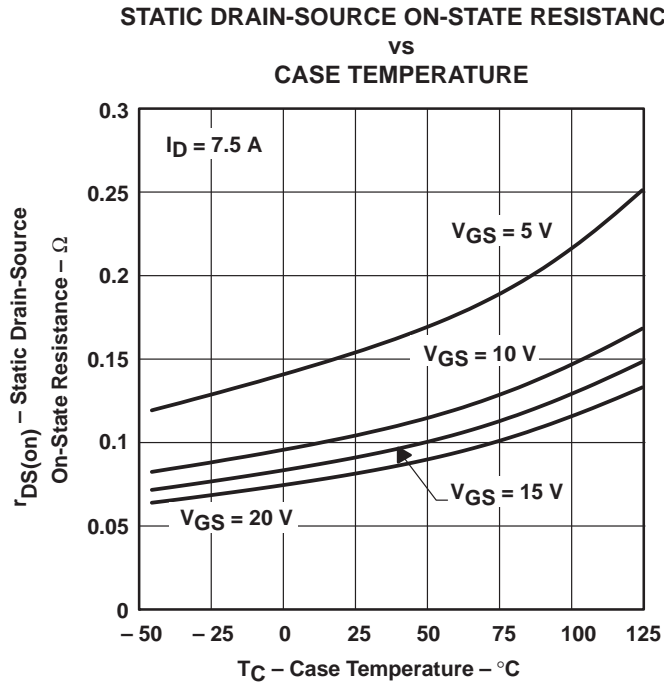


Figure 5

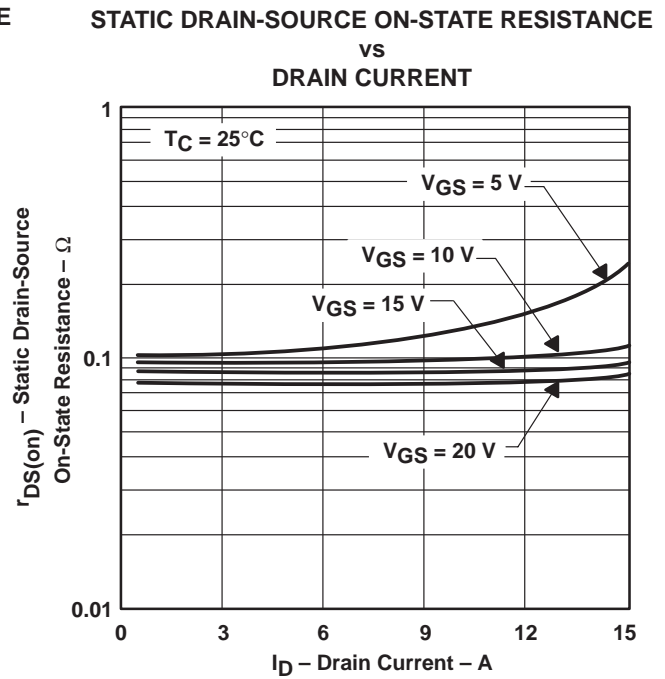


Figure 6

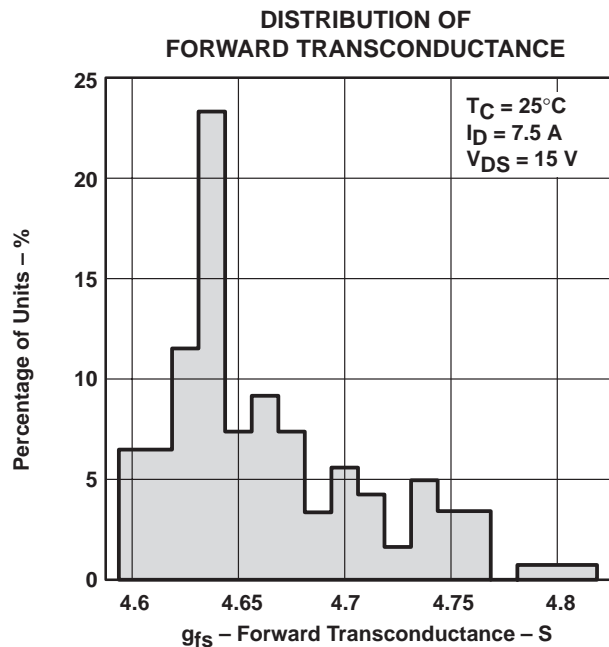


Figure 7

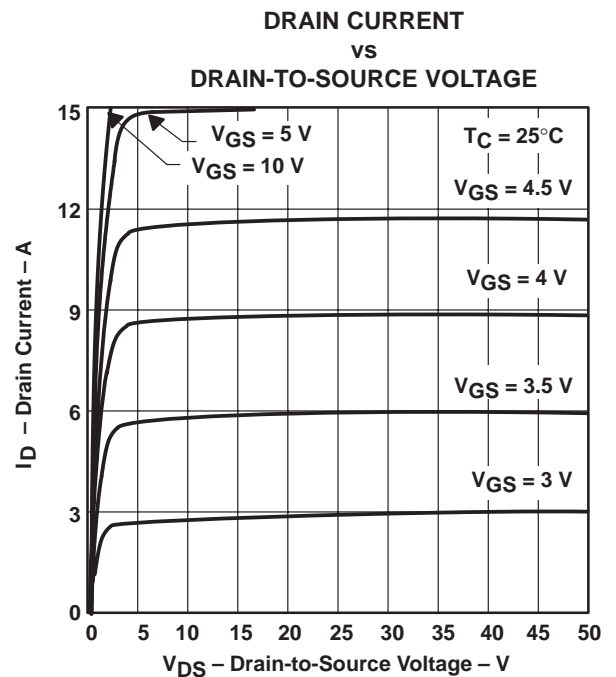
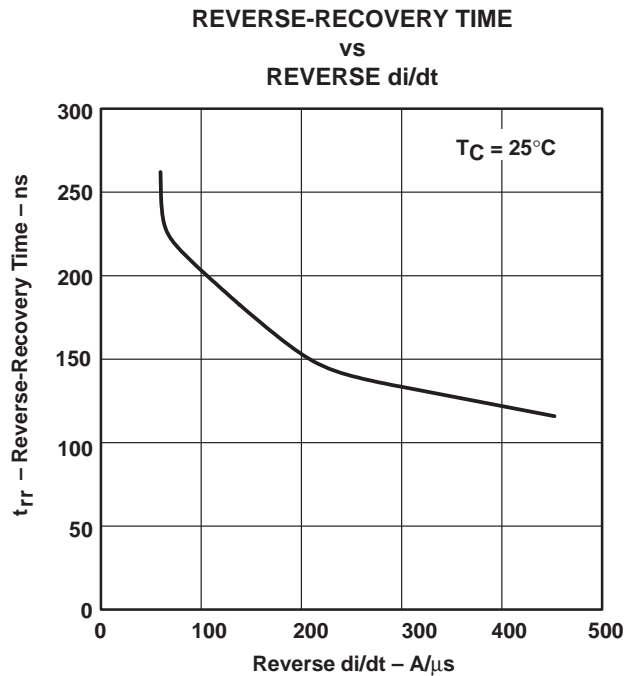
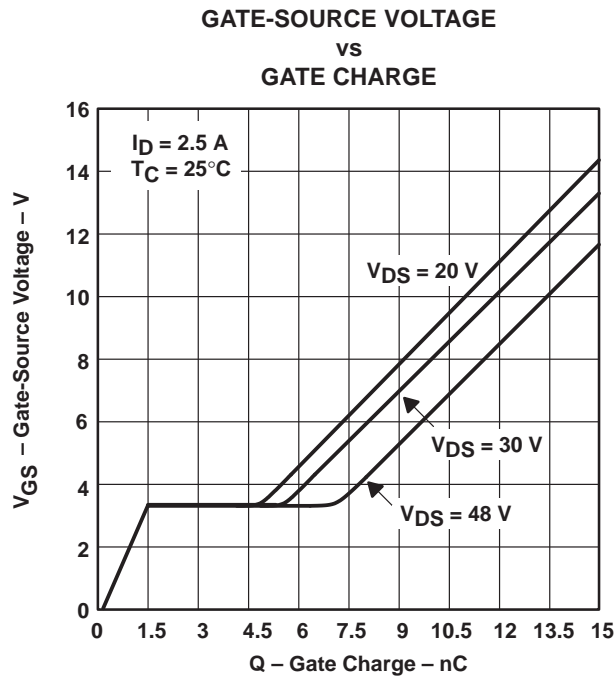
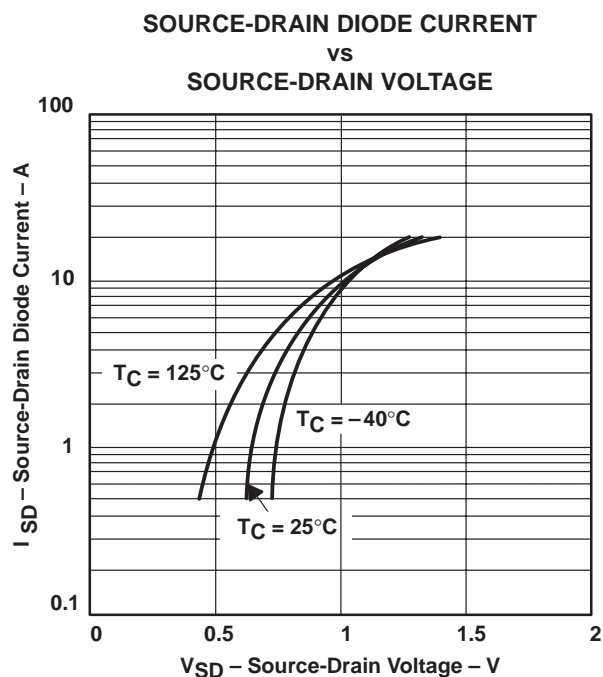
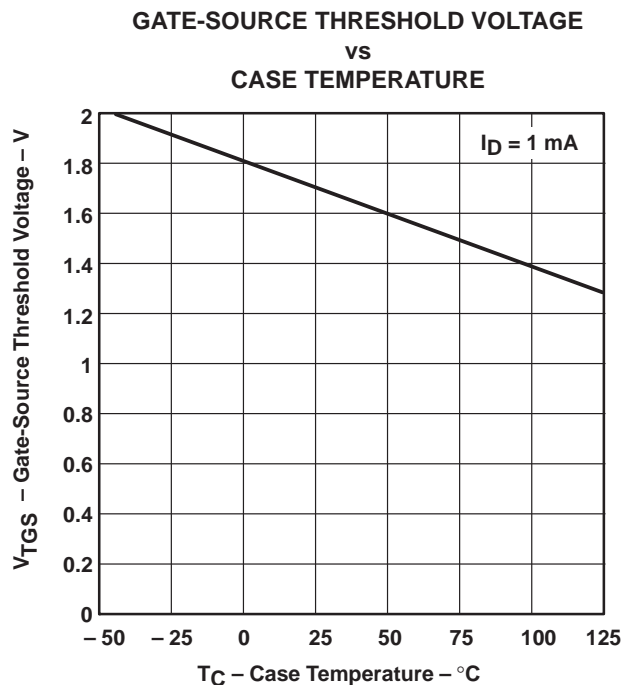


Figure 8

TYPICAL CHARACTERISTICS



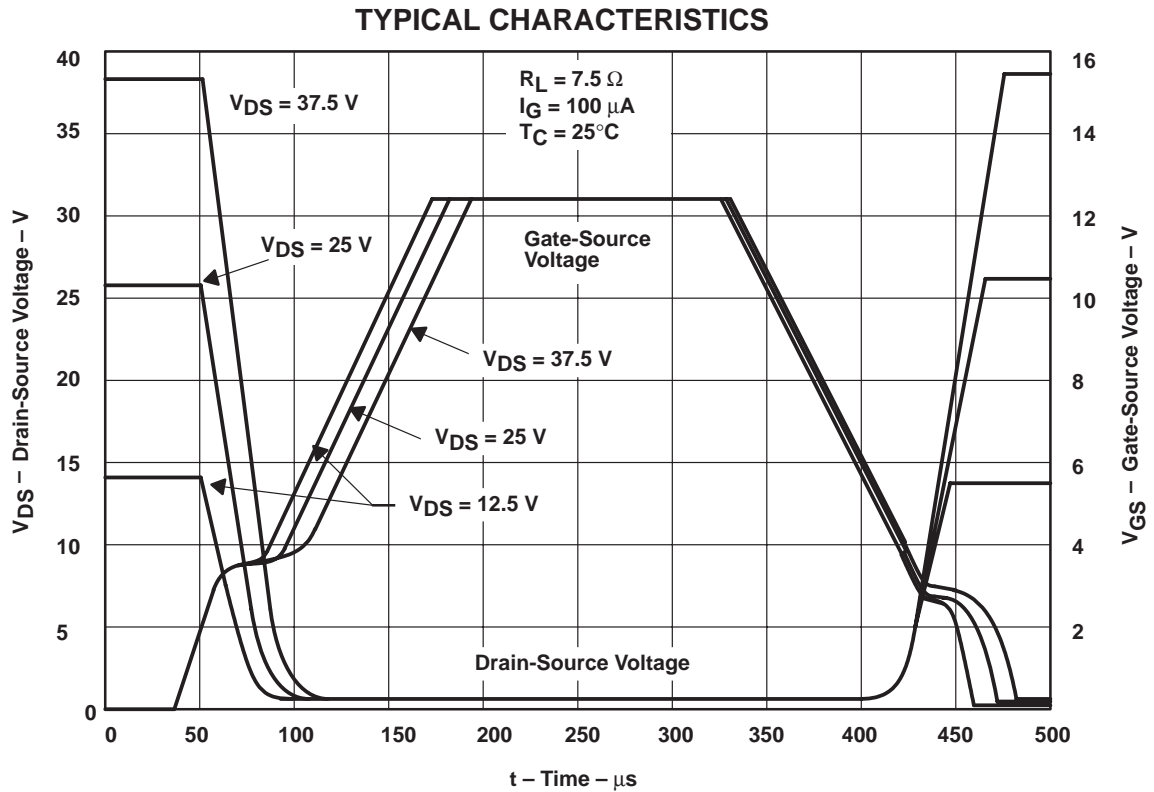


Figure 13. Resistive Switching Waveforms

THERMAL INFORMATION

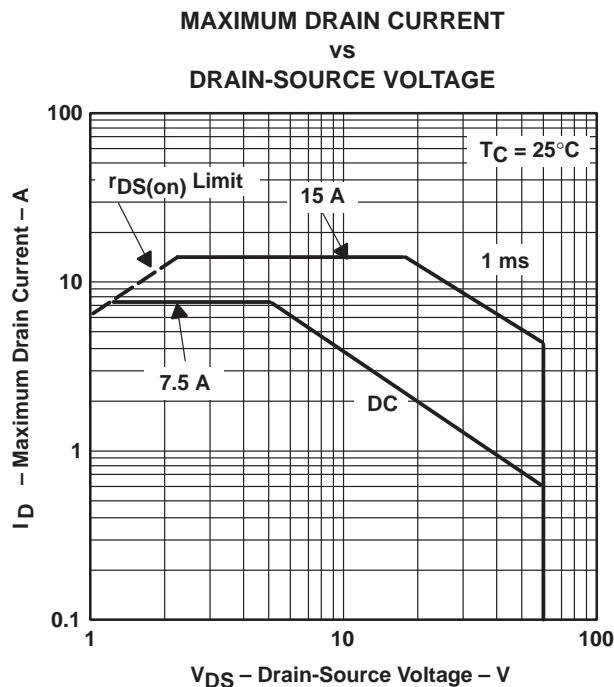


Figure 14

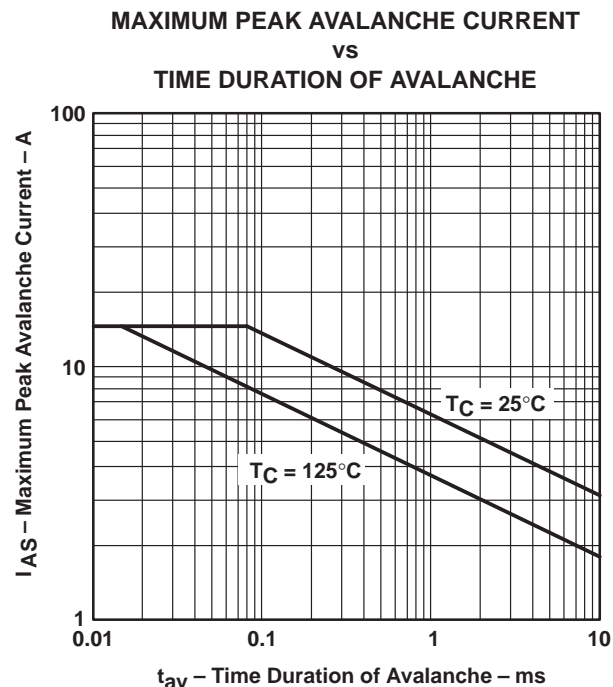
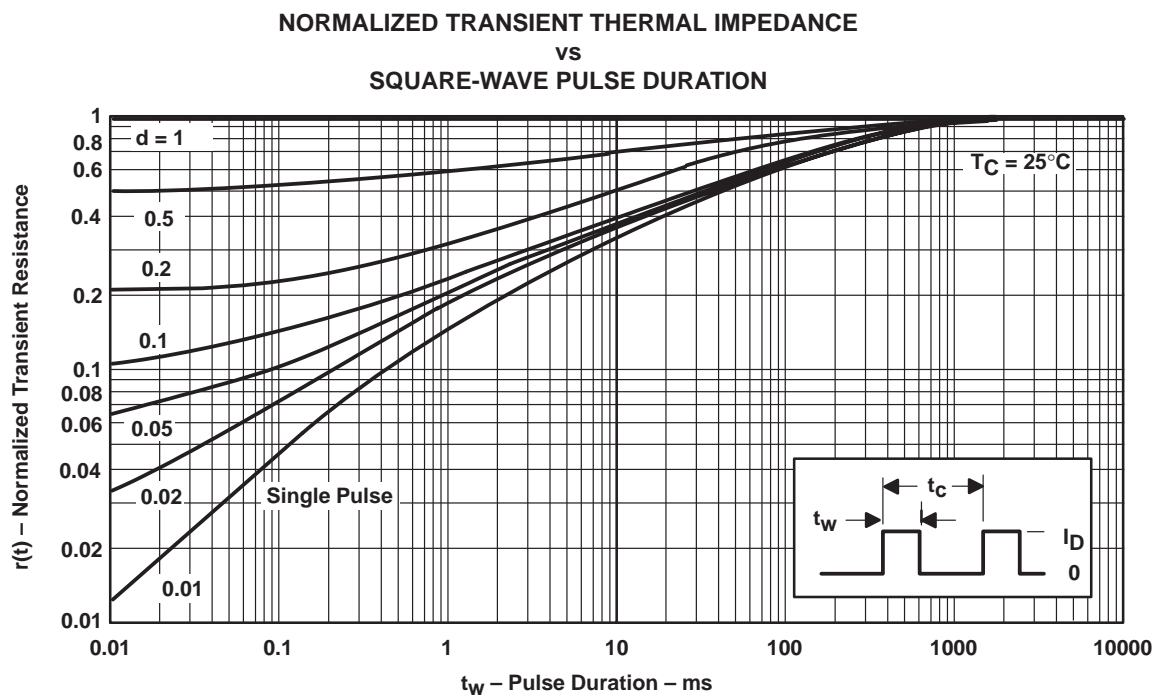


Figure 15



NOTES: $Z_{\theta JC}(t) = r(t) R_{\theta JC}$
 t_W = pulse duration
 t_C = period
 d = duty cycle = t_W/t_C

Figure 16

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